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S2	771	((emf or (electro\$1magnetic adj field)) same simulat\$4)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2005/03/24 17:22
S3	4	S2 and ((statistic\$2 adj process) or (yield adj mange\$5) or (quality adj control\$4))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2005/03/24 15:57
S4	4	S2 and ((statistic\$2 adj process) or (yield adj manag\$5) or (quality adj control\$4))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2005/03/24 17:20
S5	464	(OKADO-TAKAHIRO KATO-HIDEYUKI ISHIHARA-JINSEI).in.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2005/03/24 17:22
S6	771	((emf or (electro\$1magnetic adj field)) same simulat\$4)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2005/03/24 17:22
S7	2	S5 and S6	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2005/03/24 17:22



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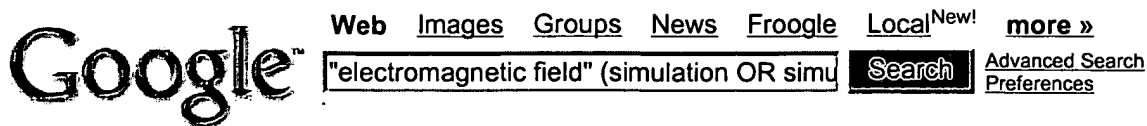
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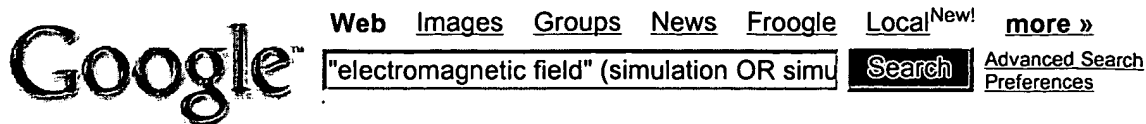


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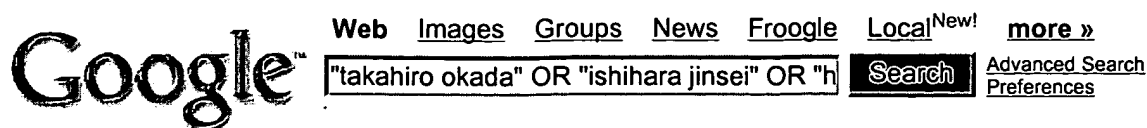
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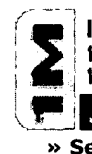
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